

승 인 원

품 명 : Multilayer Chip Antenna
Part No. : ALA931C4

	입 안	심 사	결 정
Radiopulse			

	작 성	검 토		승 인
아모텍	 2006.10.17	 2006.10.17	 2006.10.18	 2006.10.18
	10/17	10/17	10/18	10/18

2006. 10. 17

주식회사 아 모 텍

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1. 제/개정 이력

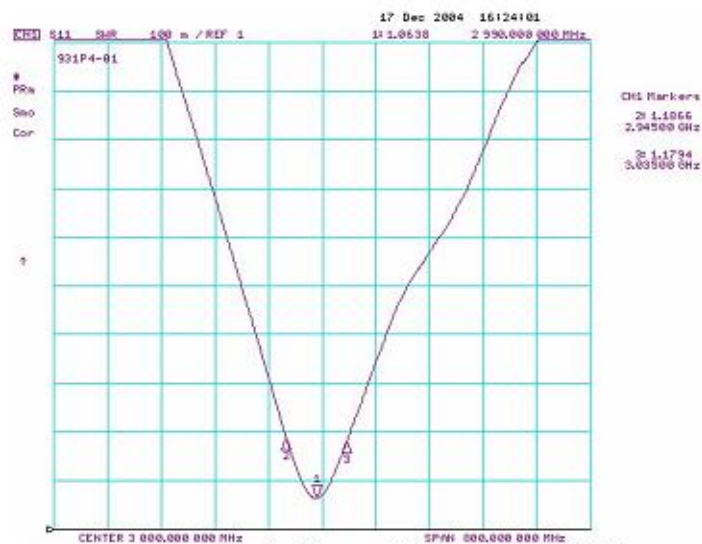
날 짜	제 목	내 용	페이지
2006.10.17		신규 작성	

2. 제품 규격

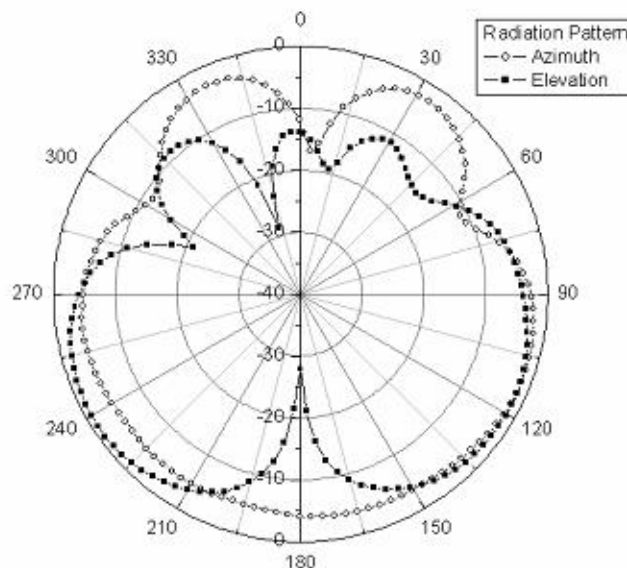
2.1 전기적 특성

구분	항목	규격	비고
1	동작 주파수	2.4 ~ 2.49 GHz	ISM band
2	정재파비	최대 2.5 : 1 @ 2990±45 MHz	수동 Jig 상에서 측정
3	방사이득	Max, 0dBi	Reference board 상에서 ISM 대역으로 매칭 후 측정 (Azimuth)
4	방사패턴	Omni-directional	
5	임피던스	공칭 50 Ω	

※ 출하검사 시 2번 항목(정재파비) 측정



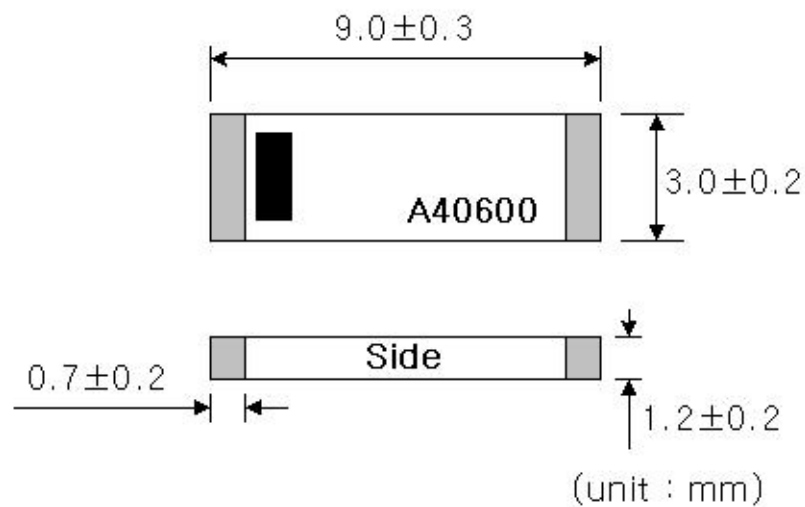
[VSWR : 수동 Jig 상에서의 측정값]



[Radiation Pattern : Bluetooth 대역에 매칭 후 측정]

2.2 기계적 특성

구분	항목	규격		단위
1	크기	가로	9.0 ± 0.3	mm
		세로	3.0 ± 0.2	
		높이	1.2 ± 0.2	
2	단위질량	97 ± 9		mg
3	동작온도	$-30 \sim +70$		℃
4	저장온도	$-40 \sim +85$		℃



[그림 Chip 안테나 dimension]

2.3 Part No. 및 Lot No. 표기법

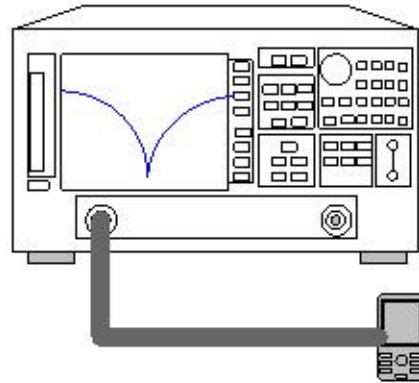
Part No.	<u>ALA</u> (1)	931 (2)	<u>C4</u> (3)
(1) : Amotech LTCC Antenna			
(2) : Chip size			
(3) : Version & 주파수규격			

Lot No.	<u>MA</u> (1)	<u>09</u> (2)	<u>A4</u> (3)	<u>0606</u> (4)	<u>01</u> (5)
(1) : Mass-product Antenna					
(2) : Chip size					
(3) : Version & 주파수규격					
(4) : 제조 년/월					
(5) : 양산 일련번호					

3. 시험방법

3.1 VSWR 측정법

사용 계측기 : Network Analyzer 8753ES

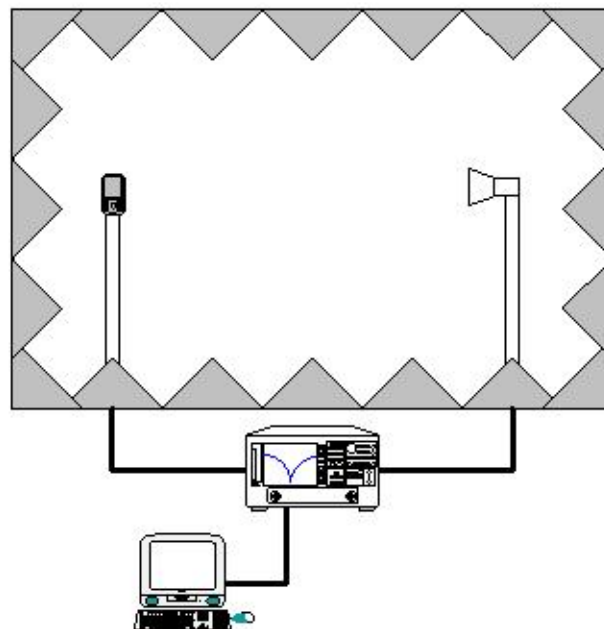


[시험절차]

- ㉔ 그림과 같이 계측기를 setup 한다.
- ㉕ $f_0 \pm 400$ MHz 대역에서 calibration 을 실시하여 50ohm 종단기를 달아 -55dB 이하임을 확인한다.
- ㉖ 측정 시료를 port cable 에 장착하여 규격주파수 대역에서 가장 높은 VSWR 을 기록 측정한다.

3.2 방사이득 측정법

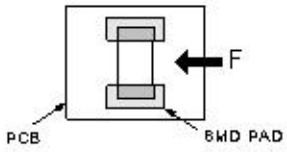
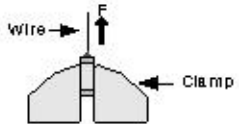
사용장비 및 계측기 : 무반향실 (8*4*4 size), Network Analyzer 8753ES



[시험절차]

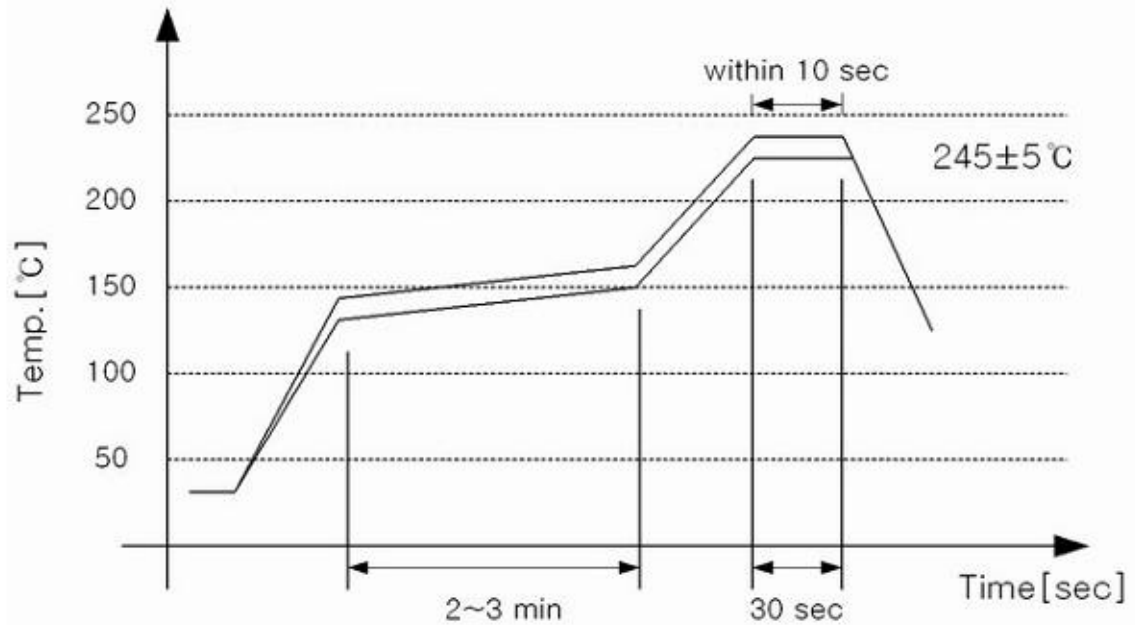
- ㉔ Reference 혼 안테나를 사용하여 calibration 을 한다.
- ㉕ 사용주파수 대역을 설정하고 그림과 같이 시료를 장착하여 측정방위에 따라 측정한다.

4. 신뢰성 시험조건

구분	항목	테스트 조건	요구 사항
1	Humidity	1. 60°C, 95%RH, 48Hr	1. 외관 손상 없음 2. VSWR 특성 만족
2	Thermal Shock	1. +80°C(30min)→1~2mim → -40°C (30min) 2. cycle 횟수 : 10 회	1. 외관 손상 없음 2. VSWR 특성 만족
3	고온 보존	1. +85°C, 96Hr	1. 외관 손상 없음 2. VSWR 특성 만족
4	저온 보존	1. -40°C, 96Hr	1. 외관 손상 없음 2. VSWR 특성 만족
5	고착 강도	1. SMT 되어 있는 시료가 PCB 에서 떨어 질 때까지 힘 F를 증가 	1. 옆으로 미는 힘 F에 의한 기계적 손상 없음 2. 힘의 세기 F > 7 kgf
6	인장 강도	1. Wire : 0.6~0.8mm Cu wire 	1. 잡아 당기는 힘 F에 의한 기계적 손상 없음 2. 힘의 세기 F > 3 kgf

5. 납땜조건 (권고사항)

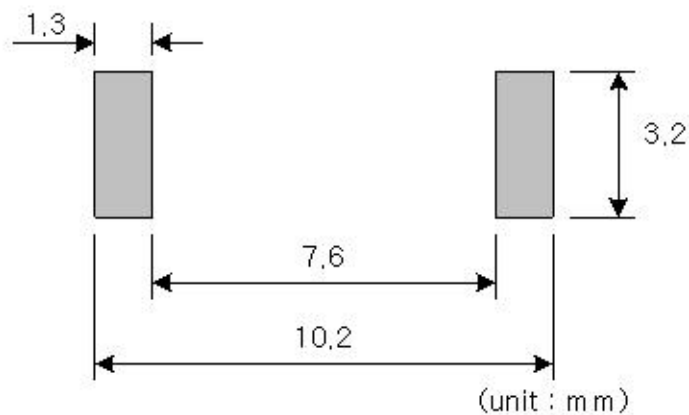
5.1 납땜온도조건 (Pb-free 조건)



안테나의 특성 저하를 막기 위해 다음과 같은 납땜 조건을 지켜야 한다.

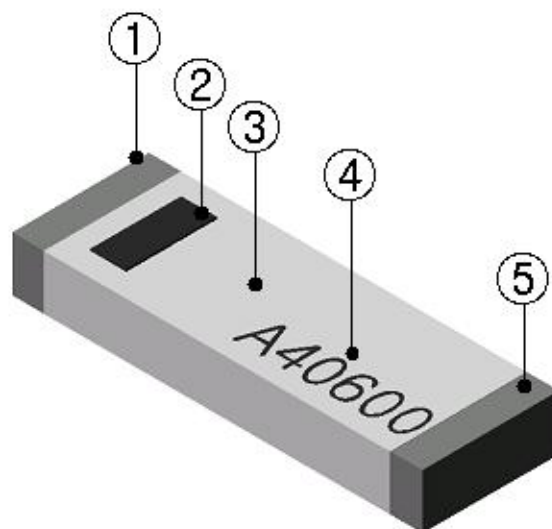
- Reflow soldering 조건으로 납땜을 진행하여야 하며, Flow soldering 을 하여서는 안 된다.
- 비활성 Flux 를 사용하여야 한다.(최대 CI 함량 0.2% 미만)
- Reflow cycle 횟수는 3 회 이내로 해야 한다.

5.2 PCB 패턴설계조건



6. 구조 및 재질

6.1 재료사양



구분	명칭	기능	재료
1	외부전극	납땜, 신호입력	Ag/Ni/Sn
2	방향 index	신호 입력단 표시	Ceramic
3	세라믹 소체	-	Ceramic
4	부품명 index	부품명, 주차 표시	Ceramic
5	외부전극	납땜	Ag/Ni/Sn

6.2 등가회로



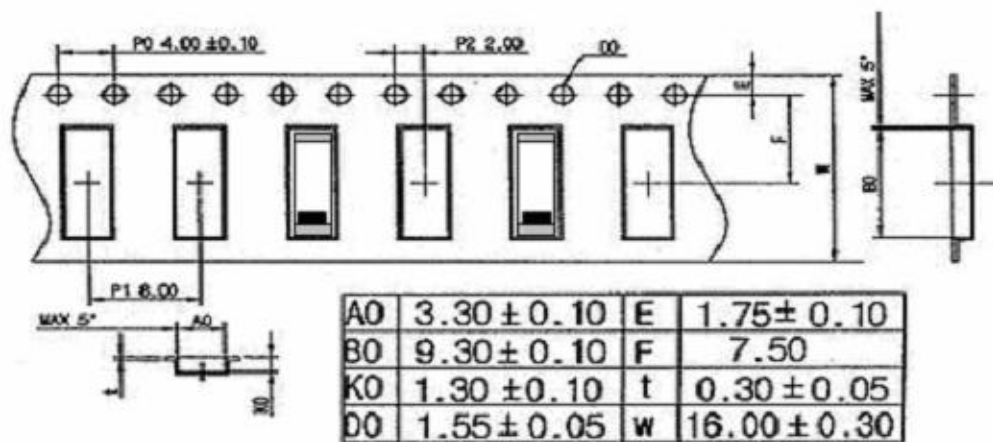
7. 주의사항

- ① 보관환경은 15~35℃, 상대습도 45~75 %의 대기에서 보관되어야 함. (MSL Level 2)
- ② 칩 안테나는 고온고습에서 방치되거나 또는 황이나 염소가스에 노출될 경우 전극의 납땜성 저하를 일으킬 수 있음.
- ③ 칩 안테나 자체 무게에 의한 세라믹 소체의 기계적 crack을 막기 위해 충격, 낙하 등을 피해야 함.

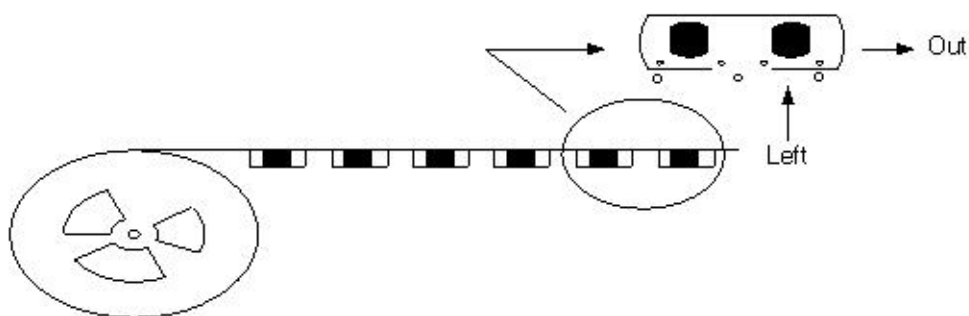
8. 포장 사양

8.1 Carrier tape 사양

8.1.1 크기

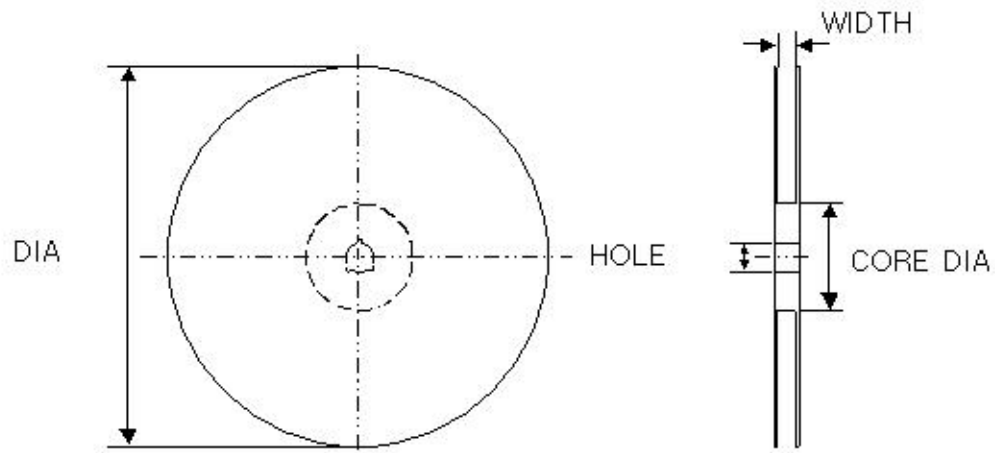


8.1.2 칩 위치



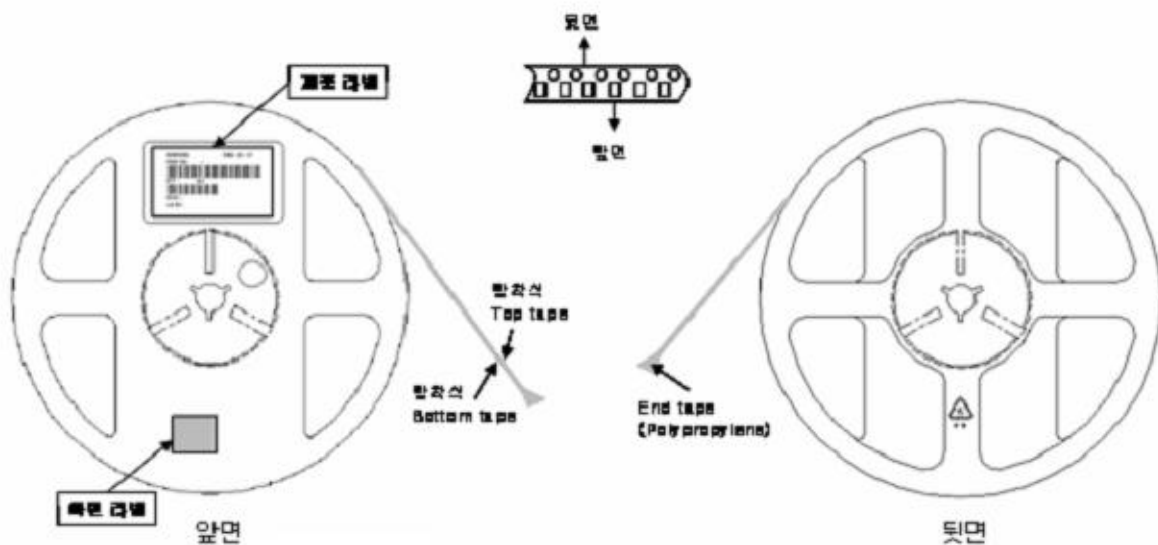
8.2 릴(Reel) 사양

8.2.1 크기



항목	DIA	WIDTH	CORE DIA	HOLE
치수(mm)	180.0 ± 0.3	17.0 ± 0.3	60.0 ± 1	13.0 ± 0.5

8.2.2 라벨 부착 및 Winding 방법



8.3 박스 포장 사양

8.3.1 소형 박스

크기 : 185 (L) × 185 (W) × 68 (H) (mm³)

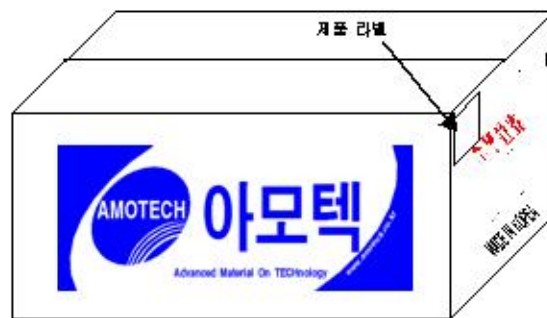
수량 : 3 reel (1,000 ea/reel × 3 reel = 3000 ea)



8.3.2 중형 박스

크기 : 365 (L) × 200 (W) × 200 (H) (mm³)

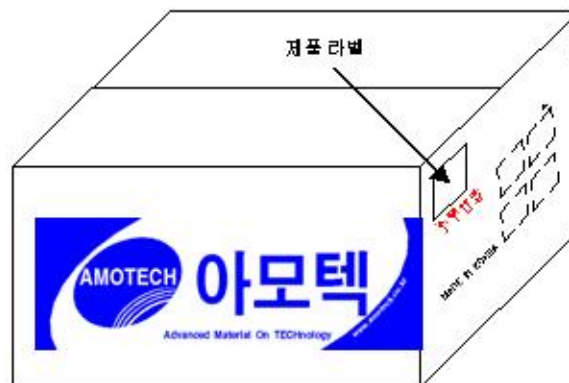
수량 : 5 소형 박스 (3,000 ea/소형 박스 × 5 소형 박스 = 15,000 ea)



8.3.3 대형 박스

크기 : 390 (L) × 390 (W) × 280 (H) (mm³)

수량 : 14 소형 박스 (3,000 ea/ 소형 박스 × 14 소형 박스 = 42,000 ea)



9. 유해물질 성적서

9.1 제품 성분 분석



Test Report No. F690501/LF-CTSGP06-24480

Date: September 25, 2006

Page 1 of 3

To: AMOTECH CO., LTD.
SBL-1L, 617
Namchon-dong
Namdong-gu
INCHEON 405-100
Korea

The following merchandise was submitted and identified by the client as :

Commodity : Multilayer Chip Antenna
SGS File No. : GP06-24480
Received Date : September 18, 2006
Test Performing Date : September 19, 2006
Test Performed : SGS Testing Korea tested the sample(s) selected by applicant with following results
Test Results : For further details, please refer to following page(s)

Jade Jang
Monet Jeong
Jully Oh
Jerry Jung
/Testing Person

SGS Testing Korea Co. Ltd.

Jeff Jang / Chemical Lab Mgr

Sample No. : GP06-24480.001
 Sample Description : Multilayer Chip Antenna
 Style/Item No. : Multilayer Chip Antenna

Heavy Metals

Test Items	Unit	Test Method	MDL	Results
Cadmium (Cd)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996), ICP	0.5	N.D.
Lead (Pb)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996), ICP	5	N.D.
Mercury (Hg)	mg/kg	US EPA 3052(1996), US EPA 6010B(1996), ICP	2	N.D.
Hexavalent Chromium (Cr VI)	mg/kg	US EPA 3060A(1996), US EPA 7196A(1992), UV	1	N.D.

Flame Retardants-PBBs/PBDEs

Test Items	Unit	Test Method	MDL	Results
Monobromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Dibromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Tribromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Tetrabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Pentabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Hexabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Heptabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Octabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Nonabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Decabromobiphenyl	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Monobromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Dibromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Tribromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Tetrabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Pentabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Hexabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Heptabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Octabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Nonabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.
Decabromodiphenyl ether	mg/kg	US EPA 3540C, GC/MS	5	N.D.

NOTE: (1) N.D. = Not detected.(<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit
 (4) - = No regulation
 (5) ** = Qualitative analysis (No Unit)
 (6) Negative = Undetectable / Positive = Detectable

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Picture of Sample as Received:



*** End ***

NOTE: (1) N.D. = Not detected. (<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit
 (4) - = No regulation
 (5) ** = Qualitative analysis (No Unit)
 (6) Negative = Undetectable / Positive = Detectable

9.2 Powder



Test Report No. F690501/LF-CTSGP06-05191

Date: March 14, 2006

Page 1 of 2

To: **AMOTECH CO., LTD.**
5BL-1L, 617
Namchon-dong
Namdong-gu,
INCHEON 405-100
Korea

The following merchandise was submitted and identified by the client as :

Commodity	: CERAMIC POWDER
SGS File No.	: GP06-05191
Received Date	: March 07, 2006
Test Performing Date	: March 08, 2006
Test Performed	: SGS Testing Korea tested the sample(s) selected by applicant with following results
Test Results	: For further details, please refer to following page(s)

Brendan Lee
Patrick An
Monet Jeong
Jinee Song
/Testing Person

Jeff Jang / Technical Mgr

SGS Testing Korea Co. Ltd.

Jason Han / Lab Director

The above certificate is the accredited test items by Korea Laboratory Accreditation Scheme (KOLAS), which signed the ILAC-MRA.

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Sample No. : GP06-05191.001
Sample Description : CERAMIC POWDER
Style/Item No. : MLS-22C

Heavy Metals

Test Items	Unit	Test Method	MDL	Results
Cadmium(Cd)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	0.5	N.D.
Lead (Pb)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	5	N.D.
Mercury (Hg)	mg/kg	US EPA 3052(1996), US EPA 6010B(1996)	2	N.D.
Hexavalent Chromium (Cr VI)	mg/kg	US EPA 3060A(1996), US EPA 7196A(1992)	1	N.D.

Picture of Sample as Received:



*** End ***

NOTE: (1) N.D. = Not detected.(<MDL)
 (2) ppm = mg/kg
 (3) MDL = Method Detection Limit
 (4) Estimated expanded uncertainty U with a coverage factor $k = 2$,
 corresponding to a level of confidence of about 95%

The above certificate is the accredited test items by Korea Laboratory Accreditation Scheme (KOLAS), which signed the ILAC-MRA.

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9.3 Paste



Test Report No. F690501/LF-CTSGP06-05192

Date: March 14, 2006

Page 1 of 2

To: AMOTECH CO., LTD.
5BL-1L, 617
Namchon-dong
Namdong-gu,
INCHEON 405-100
Korea

The following merchandise was submitted and identified by the client as :

Commodity	: AG PASTE
SGS File No.	: GP06-05192
Received Date	: March 07, 2006
Test Performing Date	: March 08, 2006
Test Performed	: SGS Testing Korea tested the sample(s) selected by applicant with following results
Test Results	: For further details, please refer to following page(s)

Brendan Lee
Patrick An
Monet Jeong
Jinee Song
/Testing Person

Jeff Jang / Technical Mgr

SGS Testing Korea Co. Ltd.

Jason Han / Lab Director

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Test Report No. F690501/LF-CTSGP06-05192

Date: March 14, 2006

Page 2 of 2

Sample No. : GP06-05192.001

Sample Description : AG PASTE

Style/Item No. : ET-1833B

Heavy Metals

Test Items	Unit	Test Method	MDL	Results
Cadmium(Cd)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	0.5	N.D.
Lead (Pb)	mg/kg	US EPA 3050B(1996), US EPA 6010B(1996)	5	N.D.
Mercury (Hg)	mg/kg	US EPA 3052(1996), US EPA 6010B(1996)	2	N.D.
Hexavalent Chromium (Cr VI)	mg/kg	US EPA 3060A(1996), US EPA 7196A(1992)	1	N.D.

Picture of Sample as Received:



*** End ***

- NOTE:**
- (1) N.D. = Not detected.(<MDL)
 - (2) ppm = mg/kg
 - (3) MDL = Method Detection Limit
 - (4) Estimated expanded uncertainty U with a coverage factor $k=2$, corresponding to a level of confidence of about 95%

The above certificate is the accredited test items by Korea Laboratory Accreditation Scheme (KOLAS), which signed the ILAC-MRA.

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